

**Notice of References Cited**

Application/Control No.

09/746,014

Applicant(s)/Patent Under  
Reexamination  
GOLDMAN ET AL.

Examiner

Fred Ferris

Art Unit

2128

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,781,430	07-1998	Tsai, Roger Yen-Luen	700/28
	B	US-5,710,700	01-1998	Kurtzberg et al.	700/29
	C	US-6,373,033 B1	04-2002	de Waard et al.	219/497
	D	US-6,207,936 B1	03-2001	de Waard et al.	219/497
	E	US-5,691,895	11-1997	Kurtzberg et al.	700/29
	F	US-2001/0054032	12-2001	Goldman et al.	706/12
	G	US-5,377,308 A	12-1994	Inoue et al.	706/52
	H	US-5,282,261 A	01-1994	Skeirik, Richard D.	706/23
	I	US-5,121,467 A	06-1992	Skeirik, Richard D.	706/10
	J	US-5,640,493	06-1997	Skeirik, Richard D.	706/25
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"DOE/Opt: A System for Design of Experiments, Response Surface Modeling, and Optimization Using Process of Device Simulation", D. Boning, IEEE Transactions on Semiconductor Manufacturing, Vol. 7, No. 2, May 1994
	V	"Design of Experiment is the best way to Optimize a Process at Minimal Cost", S. Kumar, IEEE/CHMT '90 IEMT Symposium, p 166-173, IEEE 1990
	W	"A New Methodology of Using Design of Experiments as a Precursor to Neural Networks for Material Processing: Extrusion Die Design", B. Metha, IEEE 0-7803-5489-3/99, IEEE 1999
	X	"Design of Experiments: A Tool for Continous Process Imporvement"

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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